

Date Searched: 9/3/2003

Databases Searched: USPAT, USPGPUB

Plurals: ON

Terms Searched:

L1 716/\$.ccls.

L2 (reliability or electromigrat\$4 or electro-migrat\$4 or self-heat\$4 or integrity or reliable)

L3 (layout or placement or floorplan\$4 or floor-plan\$4) same (re-arrang\$6 or rearrang\$6 or replac\$6 or relocat\$4 or reposition\$3 or mov\$3 or movement or exchang\$3 or chang\$3)

L4 1 and 2 and 3

Results: 339 hits

L5 1 and (2 same 3)

Results: 37 hits

US 6543041 B1 USPAT Scheffer, Louis K. et al. 716/10

US 6189131 B1 USPAT Graef, Stefan et al. 716/8

US 5801960 A USPAT Takano, Midori et al. 716/10

US 5581475 A USPAT Majors, Steven S. 716/10

Databases Searched: EPO, JPO, IBM TDB, Derwent

Plurals: ON

Terms Searched:

L1 (((reliability or electromigrat\$4 or electro-migrat\$4 or self-heat\$4 or integrity or reliable)) same ((layout or placement or floorplan\$4 or floor-plan\$4) same (re-arrang\$6 or rearrang\$6 or replac\$6 or relocat\$4 or reposition\$3 or mov\$3 or movement or exchang\$3 or chang\$3)))

Results: 218 hits

Date Searched: 6/18/2002

Databases Searched: USPAT, USPGPUB

Plurals: ON

Terms Searched:

L1 716/\$.ccls. and (self adj heat\$3)

Results: 4 hits

L2 (((716/\$.ccls.or 257/758.ccls or 438/637.ccls.) and (reliability or electromigrat\$4 or electro-migrat\$4 or self-heat\$4)) and (layout or placement or floorplan\$4 or floor-plan\$4)) and (overlap\$4 same row) and @pd>20010910

Resultss: 0 hit

L3 (signal same (integrity or reliability)) and (electromigrat\$4 or (self adj heat\$4) or (hot adj electron)) and (716/\$.ccls.or 257/758.ccls or 438/637.ccls.) and @pd>20010910

Results: 3 hits

US 6308303 B1 USPAT Mysore, Sriram et al. 716/5

US 6308302 B1 USPAT Hathaway, David James et al. 716/5

Database Searched: IEEE/IEEE

Terms Searched: microprocessor and (elctromigration or (self <near/2> heat*))

Results: Your search matched 3 of 775001 documents.

Date Searched: 9/17/2001

Database Searched: USPAT

Plurals: ON

Terms Searched:

L1 transistor same folding
 L2 electromigrat\$4 or (electro adj migrat\$4)
 L3 1 and 2
 Results: 1 hit
 L4 1 and 716/\$.ccls.
 Results: 20 hits
 L5 signal same (reliability or integrity)
 L6 1 and 5
 Results: 6 hits

US 5751180 A	USPAT D'Addeo, Michael Lee	327/379
US 6163877 A	USPAT Gupta, Avaneendra	716/8
US 6077308 A	USPAT Carter, Craig A. , et al.	716/8
US 5995734 A	USPAT Saika, Shunji	716/9
US 5737236 A	USPAT Maziasz, Robert , et al.	716/8
US 5675501 A	USPAT Aoki, Sachiko	716/8

Databases Searched: EPO, JPO, IBM TDB, DERWENT

Plurals: ON

Terms Searched:

L1 transistor same folding
 L2 electromigrat\$4 or (electro adj migrat\$4)
 L3 1 and 2
 Results: 0 hits
 L4 signal same (reliability or integrity)
 L5 1 and 4
 Results: 2 hits

JP 60197034 A A JPO YAMAMOTO, YOSHINOBU , CHIBA, TAKASHI , et al.

Date Searched: 9/10/2001

Database Searched: USPAT

Plurals: ON

Terms Searched:

L1 716/\$.ccls.
 L2 (reliability or electromigrat\$4 or electro-migrat\$4 or self-heat\$4)
 L3 layout or placement or floorplan\$4 or floor-plan\$4
 L4 1 and 2 and 3
 Results: 214 hits
 L5 (electromigrat\$4 or electro-migrat\$4) and self-heat\$4
 L6 1 and 3 and 5
 Results: 0 hits
 L7 overlap\$4 same row
 L8 4 and 7
 Results: 6 hits
 L9 signal same (integrity or reliability)
 L10 electromigrat\$4 or (self adj heat\$4) or (hot adj electron)
 L11 1 and 9 and 10
 Results: 4 hits

Databases Searched: EPO, JPO, IBM TDB, DERWENT

Plurals: ON

Terms Searched:

L1 (signal or constraint or cost) same (integrity or reliability)

L2 layout or placement or floorplan\$4 or floor-plan\$4

L3 1 and 2

Results: 248 hits

L4 electromigrat\$4 or (self adj heat\$4) or (hot adj electron)

L5 3 and 4

Results: 1 hits

L6 1 and 4

Results: 40 hits

US 6002857 A USPAT Ramachandran, Venkateswaran ("Venky") 716/14

US 5984510 A USPAT Guruswamy, Mohan , et al. 716/2

US 6286128 B1 USPAT Pileggi, Lawrence , et al. 716/18

US 6038383 A USPAT Young, Duane J. , et al. 716/5

US 6253361 B1 USPAT Buch, Premal 716/6

US 5737580 A USPAT Hathaway, David James , et al. 716/12

US 6195787 B1 USPAT Yokoyama, Moto 716/8

US 5822218 A USPAT Moosa, Mohamed S. , et al. 716/4

US 5648910 A USPAT Ito, Soichi 716/2

JP 2000206201 A A JPO FURUE, KATSUYA

JP 08293532 A A JPO NISHIMURA, KOICHI

JP 06302703 A A JPO YAMADA, TATSUYA , KATO, YOSHIAKI

JP 03149823 A A JPO MATSUOKA, FUMITOSHI

US 6242807 B1 USPAT Kazami, Tetsuo 257/758

US 5817574 A USPAT Gardner, Donald S. 438/637

Database Searched: IEEE/IEEE

Terms Searched: (signal or constraint or cost) and (integrity or reliability) and (layout or placement or floorplan* or floor-plan*) and (electromigrat* or (self <near/2> heat*))

Results: Your search matched 4 of 713260 documents.

Terms Searched: (integrity or reliability) and (layout or placement or floorplan* or floor-plan*) and (electromigrat* or (self <near/2> heat*))

Results: Your search matched 19 of 713260 documents.

Terms Searched: (transistor <near/4> folding) and (signal <near/10> (reliability or integrity))

Results: Your search matched [0] of [714343] documents.

Terms Searched: (transistor <near/4> folding)

Results: Your search matched 24 of 714315 documents.

1-2,4-8,10-23,25-27,29-39